

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/764,787	<b>Applicant(s)/Patent under Reexamination</b> SCHWARTZ ET AL.
	<b>Examiner</b> Tan Dean D. Nguyen	<b>Art Unit</b> 3629

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
I US	03 04	✓
	10/6/85	✓
II FOREIGN		
III NPL		
	1. Fflept 1 2. Fflept 2 3. Nfflept	
Reviewing Parent 09/764,782		✓
Reviewing (02) 101 Reg w/ John Weiss		✓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner